

J-815

Circular Dichroism

Leading the development of chiroptical instruments



Superior Performance

Superior Innovation

Superior Reliability

JASCO



Since 1961, JASCO has designed and built the finest in chiro-optical instrumentation. With 45 years of experience, the result is the best performance and reliability in the industry. Instead of using instrument components from other manufacturers, the entire instrument is designed and manufactured by JASCO. The mirrors in the J-815 are produced by a proprietary surfacing/plating/coating technique resulting in the highest reflectivity and optical throughput. The PEM is considered the heart of the CD instrument and the temperature-stabilized natural crystalline quartz prism eliminates instrumental drift.

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JASCO offers a range of measurement modes and hyphenated techniques

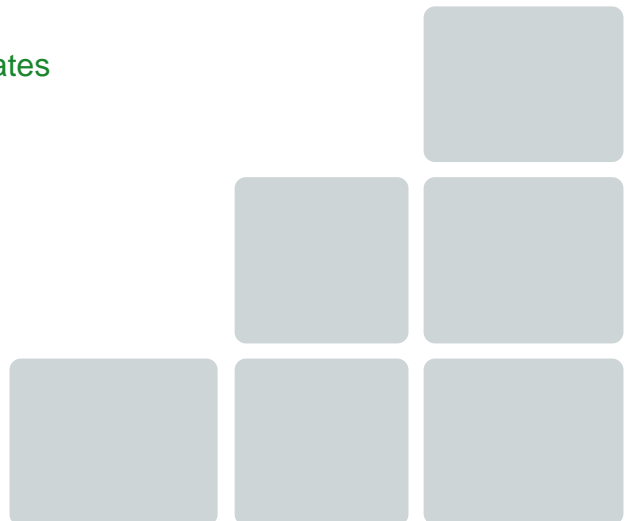


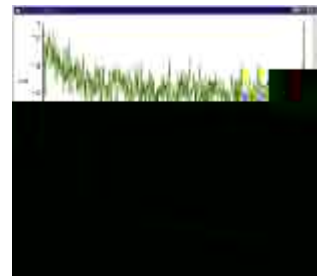
Spectra Manager™ II features

- Full control from Windows® XP Pro with 21 CFR Part 11 compliance (optional)
- Secondary structure analysis
- Denatured protein analysis
- Multi-wavelength variable temperature programming
- Curve-fitting analysis
- Macro command programming
- Publication quality printing with customizable templates
- System validation program

Optional accessories

- Peltier cell holders, single and six position
- Scanning emission monochromator
- Automatic titration system
- 2, 3, and 4 syringe stopped-flow systems
- LD, ORD, OCD attachments
- Permanent, electro and super-conducting magnets
- Near IR extended detection





SPECIFICATIONS

Light source:	150W air-cooled Xe lamp or 450W water-cooled Xe lamp (factory option)
Measurement wavelength range:	163 to 900 nm (standard detector) 163 to 1100 nm (optional detector)
Wavelength accuracy:	±0.2 nm (at 163 to 180 nm) ±0.1 nm (at 180 to 250 nm) ±0.3 nm (at 250 to 500 nm) ±0.8 nm (at 500 to 800 nm) ±2.0 nm (at 800 to 1100 nm)
Wavelength repeatability:	±0.05 nm (at 163 to 250 nm) ±0.1 nm (at 250 to 500 nm) ±0.2 nm (at 500 to 1100 nm)
Spectral bandwidth:	0.01 to 15 nm
Slit width:	1 to 3000 μm
Digital Integration Time (D.I.T.):	0.5 msec to 32 sec
Acquisition modes:	Wavelength scan (3 modes), Time scan (slow and fast kinetics), Temperature scan
Scanning speeds:	1 to 10000 nm/min (continuous scan)
Data interval:	0.025 to 10 nm (continuous scan) 0.1 to 100 nm (step scan) 0.5 msec to 60 min (time course)
CD full scale:	±10, 200, 2000 mdeg
CD resolution:	0.0005 mdeg (at ±10 mdeg full scale) 0.01 mdeg (at ±200 mdeg full scale) 0.1 mdeg (at ±2000 mdeg full scale)
Stray light:	Less than 0.0003% (200 nm)
RMS noise:	185 nm: 0.030 mdeg 200 nm: 0.020 mdeg 500 nm: 0.020 mdeg (Spectral bandwidth 1 nm, D.I.T. 16 sec)
Baseline stability:	±0.03 mdeg/hr (Spectral bandwidth 1 nm, r.
UV measurement:	
External input terminal:	
Shutter:	
Sample compartment:	
Nitrogen gas purge:	
Dimensions:	
Weight:	
Power input voltage:	
Power consumption:	
PC interface:	